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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/750,160	QIN, SIMON	
Examiner	Art Unit	
Dieu-Minh Le	2114	

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INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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EAST Search all files USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM-TDB updated.	6/15/2005	DML	
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